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SHEET 1 OF 1

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| INFORMATION DISCLOSURE CITATION PTO-1449 | ATTY. DOCKET NO. | SERIAL NO. |
| | IDT-1641 | Filed Herewith |
| | APPLICANT Integrated Device Technology, Inc. | |
| | FILING DATE Filed Herewith | GROUP unknown |

U.S. PATENT DOCUMENTS

| EXAMINER'S INITIALS | PATENT NO. | DATE | NAME | CLASS | SUBCLASS | FILING DATE |
|---------------------|------------|------------|------------------|-------|----------|-------------|
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| EXAMINER'S INITIALS | PATENT NO. | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
|---------------------|------------|------|---------|-------|----------|--------------------------|--------------------------|
| | | | | | | YES | NO |
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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| OKO | "A 2.9 μm^2 Embedded SRAM Cell with Co-Salicide Direct-Strap Technology for 0.18 μm High Performance CMOS Logic", Noda et al., 1997 IEEE. |
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| EXAMINER Douglas W. O'Brien | DATE CONSIDERED 10/20/01 |
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.